

# 75N07AGP-VB Datasheet N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub>	80	V		
$R_{DS(on)} V_{GS} = 10 V$	7	mΩ		
$R_{DS(on)}$ $V_{GS} = 4.5 \text{ V}$	9	mΩ		
I <sub>D</sub>	100	Α		
Configuration	Single			

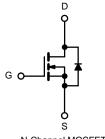
#### **FEATURES**

- TrenchFET® Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested



## **APPLICATIONS**

- Primary Side Switching
- Synchronous Rectification
- DC/AC Inverters
- LED Backlighting



N-Channel MOSFET

TO-220AB	
0	
G D S	Top View

<b>ABSOLUTE MAXIMUM RATINGS (</b>	$T_A = 25  ^{\circ}\text{C}$ , unless	otherwise noted	d)	
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V <sub>DS</sub>	80	V
Gate-Source Voltage		V <sub>GS</sub>	± 20	v
	T <sub>C</sub> = 25 °C		100a	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 70 °C		85 <sup>a</sup>	
	T <sub>A</sub> = 25 °C	I <sub>D</sub>	28.6 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		24.9 <sup>b, c</sup>	
Pulsed Drain Current (t = 100 μs)	I <sub>DM</sub>	350	Α Α	
Continuous Common Dunius Diodo Commont	T <sub>C</sub> = 25 °C	,	80 <sup>a</sup>	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	4.5 <sup>b, c</sup>	
Single Pulse Avalanche Current	. 0.1!!	I <sub>AS</sub>	30	
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	45	mJ
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		180	
	T <sub>C</sub> = 70 °C		120	W
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	5 <sup>b, c</sup>	VV
	T <sub>A</sub> = 70 °C		3.2 <sup>b, c</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	80
Soldering Recommendations (Peak Temperature)			260	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a</sup>	t ≤ 10 sec	$R_{thJA}$	15	18	°C/W	
	Steady State		40	50		
Maximum Junction-to-Case		R <sub>thJC</sub>	0.85	1.1		

#### Notes

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.



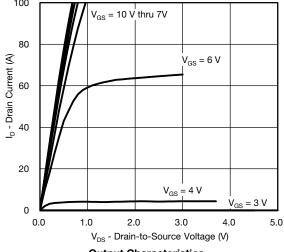
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static					l	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			37		1400
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 6.1		mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th</sub> )	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.0		3.5	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zaura Cata Valta va Duniu Commant	_	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μA
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	85			Α
		$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		7		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 6 V, I <sub>D</sub> = 15 A		7. 5		mΩ
		$V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		9		1
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_D = 20 \text{ A}$		60		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			3855		
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1120		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			376		
Total Gate Charge	$Q_g$	$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		35.5		-
		V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 6 V, I <sub>D</sub> = 10 A		22		
				18		
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		5.3		nC
Gate-Drain Charge	$Q_{gd}$			7.3		
Output Charge	Q <sub>oss</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V		57	86	
Gate Resistance	$R_{g}$	f = 1 MHz	0.5	1.3	2	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			12	24	
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_{I} = 4 \Omega$		8	16	
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		32	64	
Fall Time	t <sub>f</sub>			7	14	
Turn-On Delay Time	t <sub>d(on)</sub>			14	28	ns
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$		11	22	
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 6.0 \text{ V}, R_g = 1 \Omega$		30	60	
Fall Time	t <sub>f</sub>			8	16	
Drain-Source Body Diode Characteristic	s					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			75	А
Pulse Diode Forward Current (t = 100 μs)	I <sub>SM</sub>				150	^
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 5 A		0.76	1.1	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			38	75	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	L = 10 A dl/dt = 100 A/vo T = 25 °C		36	70	nC
Reverse Recovery Fall Time	ta	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		19		
Reverse Recovery Rise Time	t <sub>b</sub>			19		ns

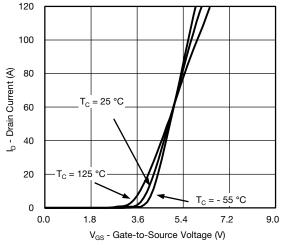
#### Notes

- a. Pulse test; pulse width  $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

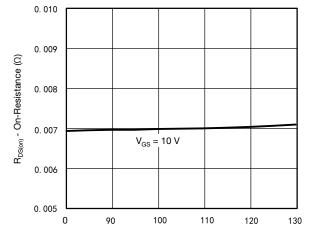
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



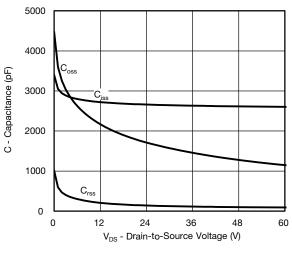








**Transfer Characteristics** 



#### On-Resistance vs. Drain Current

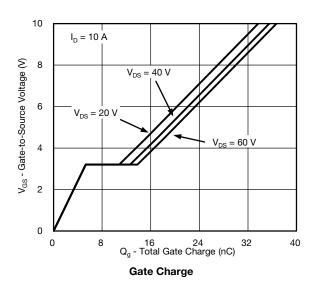
110

120

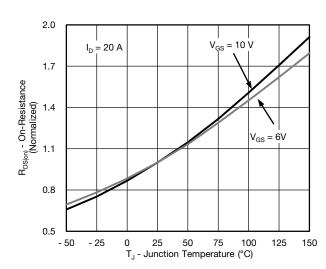
130

100

90

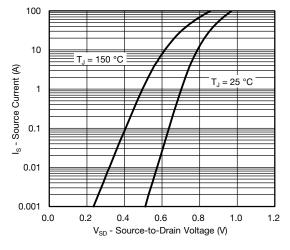


Capacitance

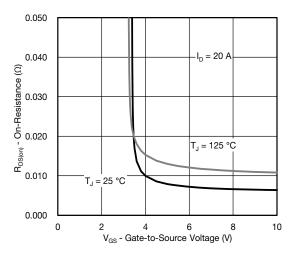


On-Resistance vs. Junction Temperature

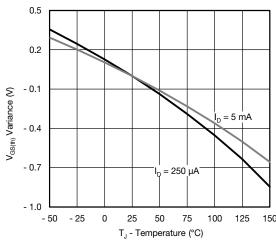




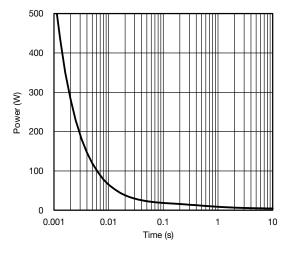
Source-Drain Diode Forward Voltage



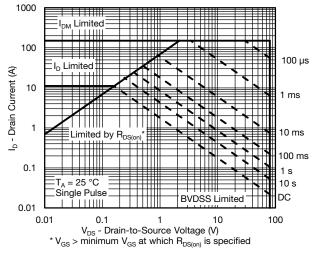
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

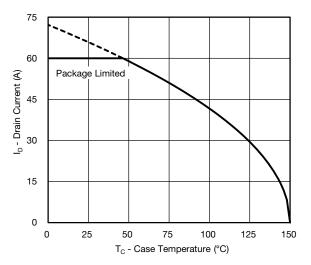


Single Pulse Power, Junction-to-Ambient

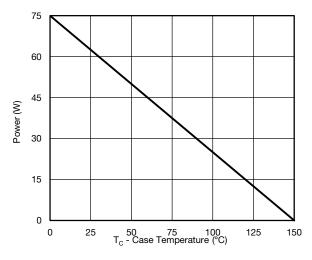


Safe Operating Area, Junction-to-Ambient

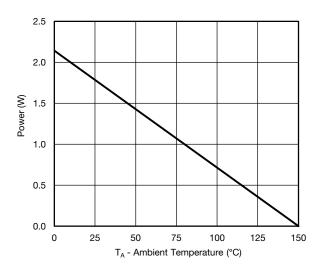




#### **Current Derating\***



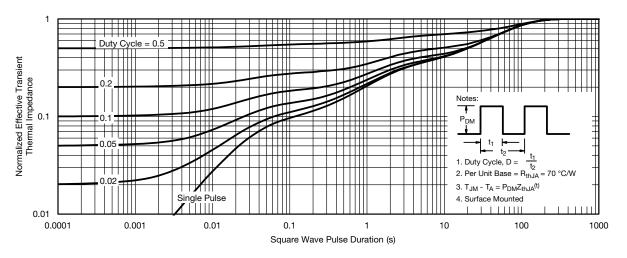




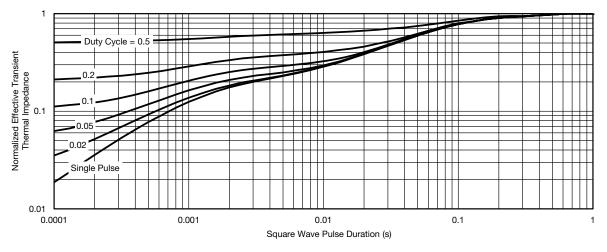
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





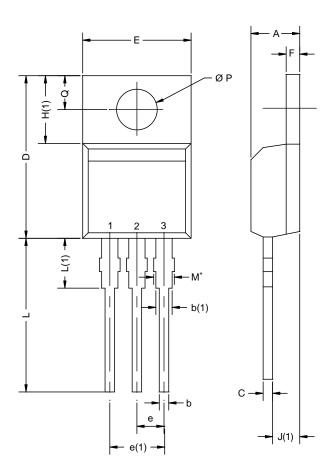
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



## **TO-220AB**



	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12					

# Notes

 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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